Abstracts

Localized circuit probing with a combined Schottky diode/scanning force microscope

D.W. Van Der Weide, V. Agrawal, T. Bork and P. Neuzil. "Localized circuit probing with a combined Schottky diode/scanning force microscope." 1998 MTT-S International Microwave Symposium Digest 98.3 (1998 Vol. III [MWSYM]): 1341-1344.

We present the first scanned probe Schottky diode used as a detector of microwave power. This technique enables direct sensing of local fields without the use of a high frequency receiver, and it can accommodate simultaneous measurement of sample topography, as well. Applications for this probe range from field mapping on planar filters to failure analysis of MMIC's.

❑ Return to main document.

Click on title for a complete paper.